2 APRIL 1980 (FOUO 6/80) 1 OF 1

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USSR Report

ELECTRONICS AND ELECTRICAL ENGINEERING
(FOUO 6/80)



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2 April 1980

USSR REPORT

ELECTRONICS AND ELECTRICAL ENGINEERING

(FOUO 6/80)

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Contents	Page
PUBLICATIONS	
Guide to Semiconductor Diodes (Boris Aleksandrovich Borodin, et al.; SPRAVOCHNIK PO POLUPROVODNIKOVYM DIODAM, 1979)	
High-Regularity Radio-Frequency Cable (Nelli Ivanovna Dorezyuk, Mikhail Fedorovich Popov; RADIOCHASTOTNYYE KABELI VYSOKOY REGULYARNOSTI, 1979).	5
Ion Etching of Microstructures (Boris Stepanovich Danilin, Valeriy Yurevich Kireyev; IONNOYE TRAVLENIYE MIKROSTRUKTUR, 1979)	7
Radiation Effects in Semiconductors (L. S. Smirnev; RADIATSIONNYYE EFFEKTY V POLUPROVODNIKAKH, 1979)	. 9
Reception of Signals With Evaluation of Their Quality (Vyacheslav Petrovich Shuvalov; PRIYEM SIGNALOV S	11

- a - [III - USSR - 21E S&T FOUO]

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CONTENTS (Continued)	Page
Screening of Microwave Structures (Yevgeniy Aleksandrovich Vorob'yev; EKRANIROVANIYE SVCH KONSTRUKTSIY, 1979)	15
Superlong-Distance Propagation of Short Radio Waves (Aleksandr Viktorovich Gurevich, Yelena Yevgen'yevna Tsedilina; SVERKHDAL'NEYE RASPROSTRANENTYE KOROTKIKH RADIOVOLN, 1979)	17

- b -

PUBLICATIONS

GUIDE TO SEMICONDUCTOR DIODES

Moscow SPRAVOCHNIK PO POLUPROVODNIKOVYM DIODAM (Guide to Semiconductor Diodes) in Russian 1979 signed to press 5 Oct 79 pp 2, 431-432

[Annotation and table of contents from book by Boris Aleksandrovich Borodin, Vyacheslav Mikhaylovich Dronevich, Rimma Vasil'yevna Yegorova, Artem Stenanovich Kozyrev and Iosif Fedorovich Nikolayevskiy, editors, Izdatel'stvo Svyaz', 47,000 copies, 432 pages]

[Text] This volume examines a wide variety of commercially-manufactured diodes, encompassing all areas of diode utilization. Volt-ampere characteristics are given for all types of diodes, as well as parameters, their physical significance, as well as recommendations on utilization.

This manual is intended for engineer-technician personnel and can be useful to undergraduates and graduate students at radio engineering schools.

	CONTENTS	Page
	duction	3
I.	Operating Principles and Parameters of Diodes	6
II.	Rectifier Diodes	35
	D7A-D7Zh	35
	KD102A, KD102B	39
	KD103A, KD103B	43
	KD104A	47
	KD105B-KD105G	49
	GD107A, GD107B	53
	AD110A	55
	KD202A-KD202\$	58
	KD203A-KD203D	62
	KD204A-KD204V	66
	KD205A-KD205L	70
	D206-D211	73
	KD206A-KD206 V	76
	KD208A	78
	KD209A-KD209 V	81
		86
	KD210A-KD210G	90
	MD217, MD218	70

1

	page 4 page 5	92
	D226A-D226D	94
	D229V-D229L D242-D248, D242A-D248A, D242B-D248B	98
	Rectifier Piles and Units	100
111.		100
	KTs106A-KTs106D	104
	KTs201A-KTs201Ye	110
	KTs401A-KTs401D KTs402A-KTs402I, KTs403A-KTs403I, KTs404A-KTs404I, KTs405A-	
		115
	KTs405I	118
	KTs407A D1006A, D1007A, D1008A	121
	D1009, D1009A, D1010, D1010A, D1011, D1011A	125
~	Multipurpose Diodes	132
IV.		132
	D2B-D2I	134
	D9B-D9L D219A, D22O, D22OA, D22OB	139
	GD402A, GD402B	142
17	Pulse Diodes	145
v.	D18, D20	145
	D310	148
	D311, D311A	150
	D312, D312A	154
	KD503A, KD503B	158
	KD504A	163
	GD507A	165
	GD508A, GD508B	168
	KD509A, KD510A	173
	GD511A-GD511V	176
	KD512A	178
	KD513A	180
	KD518A	184
	KD520A	187
	KD521A-KD521V	190
	KD522A, KD522B	194
VI.		197
	2DC111A_VDC111V	197
	KDS413A-KDS413V, KDS414A-KDS414V, KDS415A-KDS415V	200 202
	KDS523A-KDS523G	202
	KDS525A-KDS525L	208
	KDS526A-KDS526V	209
	KD901A-KD901G	212
	KD903A, KD903B	214
	KD904A-KD904Ye	219
	KD906A-KD906Ye	222
	KD907B, KD907G	224
	KD908A	224
	KD910A-KD910V	228
	KD911A, KD911B	231
	KD913A	233
	VD01/A . VD01/V	2,7,3

2

	VD0174	237
	KD917A	239
	KD918B, KD918C	241
	KD919A	245
VII.		245
	KS107A KS133A, KS139A, KS147A, KS156A, KS168A	247
	KS162A, KS168V, KS170A, KS182A, KS191A, KS210B, KS213B	251
		260
	KS191M-KS191R	263
	KS1915-KS191F	267
	KS211B-KS211D	271
	D219S, D220S, D223S	273
	KS433A, KS439A, KS447A, KS456A, KS468A	277
	KS482A, KS510A, KS515A. KS518A, KS522A, KS527A	279
	KS515G, KS520V, KS524G, KS531V, KS547V	283
	KS539G, KS568V, KS582G, KS596V	286
	KS533A	200
	KS620A, KS620AP, KS630A, KS630AP, KS650A, KS650AP, KS680A,	289
	KS680AP	292
	D808-D811, D813	295
	D814A-D814D	298
	D815A, AP-D815I, IP	302
	D816A, AP-D816D, DP	
	D817A, AP-D817G, GP	304
	D818A-D818Ye	307
VIII	.Variable-Capacitance Diodes	312
	KV101A	312
	KV102A-KV102V	313
	KV103A, KV103B	315
	KV104-A-KV104Ye	318
	KV105A, KV105B	322
	KV106A, KV106B	325
	KV107A-KV107G	327
	KV109A-KV109G	329
	KV110A-KV110Ye	332
	KVS111A, KVS111B	335
	D901A-D901Ye	338
	D902	340
IX.	Light-Emitting Diodes and Infrared Radiators	343
1	KL101A-KL101V	343
	AL102A-AL102G	346
	AL103A, AL103B	349
	KL104A	352
	AL106A-AL106V	355
	AL107A, AL107B	358
	AL108A	360
	AL109A	363
	AL112A-AL112V	365
	AL112G-AL112I	367
	AL112K-AL112M	370
	ALIZE ALIZE	371

3

FOR OFFICIAL USE ONLY

	AL307A, AL307B	374
х.	Tunnel and Backward Diodes	378
Λ.	AI101A-AI101I, AI201A-AI201I	378
	GI103A-GI103G	381
		384
	AI301A-AI301G	387
	GI304A, GI304B	389
	GI305A, GI305B	391
	GI 307A	393
	GI401A, GI401B	395
	AI402A, AI402B, AI402G, AI402Ye, AI402I	*
	G1403A	402
XI.	Thyristors	404
	KU101A, KU101B, KU101G, KU101Ye	404
	KU201A-KU201L	410
	KU203A-KU203I	413
	KU204A-KU204V	416
	KU208A-KU208G	419
	•••	424
	D235A-D235G	428
	D238A-D238Ye	

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3024

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PUBLICATIONS

HIGH-REGULARITY RADIO-FREQUENCY CABLE

Moscow RADIOCHASTOTNYYE KABELI VYSOKOY REGULYARNOSTI (High-Regularity Radio-Frequency Cables) in Russian 1979 signed to press 29 Jun 79 pp 2, 104

[Annotation and table of contents from book by Nelli Ivanovna Dorezyuk and Mikhail Fedorovich Popov, Izdatel'stvo Svyaz', 2,700 copies, 104 pages]

[Text] This book discusses theory and practice of engineer calculation of coaxial cables with random and periodic irregularities.

The authors present the principal methods of mathematical description of processes in an irregular cable and determination of frequency characteristics in relation to parameters of irregularities in the cable. The authors present the interrelationship between input and output characteristics and examine the basic techniques of designing high-regularity cables, the specific features of their manufacturing process and methods of a evaluating frequency characteristics.

This book is intended for engineer-technician personnel employed in development, design and utilization of high-regularity coaxial cables.

. Contents	Page
Foreword	3
Introduction	4
Chapter 1. Theoretical Calculation of Wave Impedance	6
1.1. Coaxial Cable Wave Impedance	6
1.2. Basic Formulas for Calculating Wave Impedance	7
1.3. Mathematical Modeling in Designing Coaxial Cables	13
Chapter 2. Irregularities in Coaxial Cables	18
2.1. Basic Terminology	18
2.2. Design and Manufacturing Irregularities	20
2.3. Spectral Analysis Method in Studying Irregularities	24

5

FOR OFFICIAL USE ONLY

Chapte	er 3. Frequency Characteristics of Irregular Cable	27
3.1.	Selection of Irregular Cable Model	27
3.2.	Methods of Calculating Frequency Characteristics of an Irregular Cable	29
3.3.	Topological Method of Analysis of Frequency Characteristics of an Irregular Cable	31
3.4.	Analysis of Frequency Characteristics of Irregular Cable, Employing Resolution Into Harmonic Components	41
3.5.	Computer Calculation of Frequency Characteristics of a	50
3.6.	Cable With Periodic Irregularities Specific Features of Calculating Cable Frequency Response	52
3.7.	With Quasi-Periodic Irregularities Statistical Characteristics of an Irregular Cable	55
Chapt	er 4. Methods of Experimental Investigation of Character-	
•	istics of an Irregular Cable	61
4.1.	General	61
4.2.	Time-Domain Reflectometry Method	62
4.3.	Frequency Reflectometry Method	67
4.4.	Measurement of Nonuniformity of Attenuation Frequency Response	74
4.5.	Measurement of Standard Deviation of Phase-Frequency Response of an Irregular Cable	77
Chapt	er 5. Design and Characteristics of Broadband Phase-Stable Coaxial Cable	83
5.1.	Design Elements and Materials	83
5.2.		84
5.3.	Flexible Broadband Radio-Frequency Cables	89
Chapt	er 6. Features of Manufacture of Broadband Coaxial Cables	94
6.1.	Optimal Conditions for Insulation on Extruding Machines	94
6.2.	Methods of Calibrating Solid and Semi-Air Insulation	98
6.3.	Applying Smooth and Crimped Outer Conductors	99
Bibli	ography	103
	IGHT: Izdatel'stvo "Svyaz," 1979 -3024]	
3024 CSO:	1860	

6

PUBLICATIONS

UDC 621.382.8

ION ETCHING OF MICROSTRUCTURES

Moscow IONNOYE TRAVLENIYE MIKROSTRUKTUR [Ion Etching of Microstructures] in Russian 1979 signed to press 23 Mar 79 pp 2, 103

[Annotation and table of contents from book by Boris Stepanovich Danilin and Valeriy Yurevich Kireyev, Sovetskoye radio, 8,000 copies, 104 pages]

[Text] The authors give the classification of the etching processes for materials used in manufacturing microelectronic devices and examine the mechanisms of ion sputtering and the dependence of the sputtering factor and the rate of ion etching on the physical, chemical, and technological factors. They analyze the special characteristics of the modes of evacuation, image transport, selection and processing of masking materials, as well as the radiation defects occurring during ion etching. Various systems of ion etching, methods and devices for controlling this process and the prospects of its use in the production of microelectronic products are examined. Practical recommendations are given for the selection and calculation of technological parameters of ion etching for various materials and geometry of sputtering devices for its realization.

The book is intended for technologists of the electronic industry and developers of new types of equipment, as well as for undergraduate and graduate students of higher educational institutions.

Figures -- 45, tables -- 12, bibliography -- 158 items.

Contents

For	reword	Page 3
Int	roduction	5
1.	Ion Etching Mechanism	20
2.	Sputtering Factor of Materials	26
3.	Rate of Ion Etching	38
4.	Effects of Chemically Active Residual Gases on Ion	
	Etching of Materials	41

7

FOR OFFICIAL USE ONLY

5.	Selection of the Evacuation Mode and Vacuum Systems	47
6.	Special Characteristics of Image Transport from the	
	Mask to the Working Material During Ion Etching	51
7.	Selection and Processing of Masking Materials	
•	During Ion Etching	59
8.	Radiation Defects and Changes in Electrophysical	
-•	Parameters of Microelectronic Structures During	
	Ion Etching	67
Q	Classification of Ion Etching Systems	70
	High-Frequency Diode Systems	72
	Systems with Independent Ion Sources	79
	Direct-Current Diode Systems	83
	Triode Systems	85
1/.	Control of the Rate of the Removal of the Material and	
14.	Thickness of the Films in the Process of Ion Etching	86
	Thickness of the Films in the Floress of Ion Bonning	
Bib	liography	95
COP	YRIGHT: Izdatel'stvo "Sovetskoye radio," 1979	
[13	8-10233]	

10,233 CSO: 1860

PUBLICATIONS

RADIATION EFFECTS IN SEMICONDUCTORS

Novosibirsk RADIATSIONNYYE EFFEKTY V POLUPROVODNIKAKH (Radiation Effects in Semiconductors) in Russian 1979 signed to press 31 May 79 pp 2, 221

[Annotation and table of contents from book by Prof L. S. Smirnov, editor, Izdatel'stvo Nauka, 1,550 copies, 224 pages]

[Text] This volume contains original and survey articles on current problems of radiation physics of semiconductors. The theoretical articles examine problems of formation, accumulation and annealing of various multiple-vacancy defects, as well as problems connected with computer modeling of structural imperfections. The experimental studies deal with features of formation of defects in the surface layer of a semiconductor and photoluminescence of irradiated crystals. The authors stress the role of thermally activated rearrangements both of radiation defects and defect-impurity complexes present in the original crystals.

This volume is intended for scientific workers and engineers employed in the area of radiation physics of semiconductors, defects of structure or inhomogeneous systems.

	Contents	Page
Ed:	itor's Foreword	3
G.	V. Gadiyak and S. F. Ruzankin. Numerical Modeling of Imperfections in Semiconductors by Quantum Chemical Methods	6
Α.	I. Baranov. Accumulation of Defects and Processes of Amorphization During Ion Bombardment of Semiconductors	23
٧.	V. Bolotov and A. V. Vasil'yev. High-Temperature Irradiation of Silicon and Germanium	61
N.	N. Gerasimenko, N. N. Kibalina, and V. F. Stas'. Surface Layer in Irradiated Silicon	78
L.	N. Safronov. Low-Temperature Photoluminescence of Irradiated Silicon	101
Α.	I. Baranov. Annealing of Complex Defects in Irradiated Semi- conductors	130

9

FOR OFFICIAL USE ONLY

V. P. Kazantsev. Electric Constants of Irradiated Semiconductors
V. D. Akhmetov, V. V. Bolotov, and A. V. Vasil'yev. Interaction
of Defects in Silicon During Heat Treatment

205

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3024

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10

PUBLICATIONS

UDC 621.391

RECEPTION OF SIGNALS WITH EVALUATION OF THEIR QUALITY

Moscow PRIYEM SIGNALOV S OTSENKOY IKH KACHESTVA [Reception of Signals with Evaluation of Their Quality] in Russian 1979 signed to press 19 Apr 79 pp 2, 236-237

[Annotation and table of contents from a book by Vyacheslav Petrovich Shuvalov, Izdatel'stvo Svyaz', 4,600 copies, 240 pages]

[Text] The author examines the methods of evaluating the quality of signals and gives recommendations for their use in systems for transmitting discrete messages for increasing their correctness. Along with mathematical analysis of the methods for evaluating quality of signals, he treats the problems of technical realization of detectors of signal quality and gives results of experimental studies characterizing the effectiveness of their use.

Contents

List of Mos	et Frequent Notations	Page 3
Foreword		5
Introduction	on	6
Chapter 1.	General Problems of the Theory of Element-by-Element	
-	Reception with Evaluation of Signal Quality	12
1.1.	Probability Characteristics	12
1.2.	Criteria of Comparison and Optimization of	
	Receivers with Indirect Method of Error Detection	15
1.3.	Synthesis of Quality Detectors of Receivers with	
	Erasing for Element-by-Element Reception of Signals	24
1.4.	Control by the Minimum and Maximum	27
	Losses During Nonoptimal Evaluation of Signal Quality	30
1.6.	Informativeness of Parameters Used for Evaluating	
	Signal Quality	36
1.7.	Special Characteristics of the Evaluation of Signal	
	Quality by the Probability of Incorrect Reception	
	When there Are More than two Quality Grades	42

11

Chapter 2.	Phase Modulation	43 43
2.1. 2.2.	General Information Reception of Phase-Modulated Signals with Evaluation	43
	of Their Quality Under the Effect of Narrow-Band Fluctuation Noise	45
2.3.	Quality Control of Signals with Relative Phase Modulation During Correlational Reception Under	
2.4.	the Effect of Narrow-Band Fluctuation Noise Reception of Frequency Modulated Signals with	50
2.4.	Evaluation of Their Quality in Communication	56
2.5.	Channels with Pulsed Noise Quasi-Optimal Reception with Evaluation of Signal	
2.6	Quality Under the Effect of Pulsed Noise Control of the Parameters of Received Phase-	60
2.6.	Modulated Signals Under the Effect of Pulsed Noise	62
2.7.	Effects of Intersymbol Interference on the Operational	69
2.8.	Effectiveness of a Quality Detector Calculation of Probability Characteristics Under the	09
2.0.	Effect of a Complex of Noise in the Channel	75
2.9.	Determination of Probability Characteristics with	
	Consideration for the Effects of Linear Circuits of	80
	Channels with Pulsed and Fluctuation Noise	80
Chapter 3.	Frequency Modulation	83
3.1.	General Information	83
3.2.	Optimal Reception with Evaluation of Signal Quality	
	Under the Effect of Narrow-Band Fluctuation Noise	86
2.2	in the Channel [3.20] Control of Individual Parameters of Received Signals	00
3.3.	and of Their Aggregate in a Channel with Narrow-Band	
	Fluctuation Noise	91
3.4.	Synthesis of a Digital Receiver of Frequency-	gia.
	Modulated Signals Under the Conditions of the	
	Influence of Fluctuation Noise	98
Chanter 4.	Distortion of a Binary Signal	101
4.1.	Characteristics of a Random Process at the Output of	
	a Binary Device	101
4.2.	Fringe Distortions and Splitting of Binary	107
4.3.	Signals A Mass of Distortions and Its Interconnection with	107
4.5.	Fringe Distortions and Splitting	111
_		100
Chapter 5.	Problems of Quality Evaluation of Binary Signals Optimal Registration and Evaluation of Signal	120
5.1.	Quality When the Readings Are Affected Independently	120
5.2.	Optimal Algorithm for Processing Elementary Elements for a Case When the Readings Form a Simple Markoff	
	Chain	125

12

5.3.	Effectiveness of the Registration and Control of	
	Quality in Selecting a Step Weight Function [5.2]	128
5.4.	Other Methods for Evaluating the Quality of Binary	
	Signals	135
Ohantan 6	Reception of Compound Signals with Evaluation of Their	
Chapter 6.	Ouality	138
٤ 1	Evaluation of the Quality of a Compound Signal	138
6.1.	Models of Error Flow and Erasure Flow	143
6.2.	Calculation of Probability Characteristics in	143
6.3.	Application to a Code Combination	148
<i>()</i>	Comparison of the Effectiveness of Systems with the	140
6.4.	Code and Indirect Methods of Error Detection	152
	Combined Use of Code and Indirect Methods of Increas-	172
6.5.		156
	ing Fidelity Algorithm for the Processing of Units with Preliminary	150
6.6.	Algorithm for the Processing of Units with Fleriminary	
	Clearing of Code Combinations from Errors [6.19,	161
	6.20]	101
0h 7	Some Problems of the Quality Evaluation of Communi-	
Chapter 7.	cation Channels	167
7 1		167
7.1.		10,
7.2.	Which the Value Being Measured Gets into the Pre-	
		173
7 7	scribed Intervals Evaluation of the Quality of a Channel with Pulsed	173
7.3.	Noise Under the Conditions of Parametric Indeter-	
		178
- ,	minacy	170
7.4.		184
	Frequency Rate	104
.	v C. D. in a few the Headward on of Cional Ovality	
Chapter 8.	Use of Devices for the Evaluation of Signal Quality	187
	in Data Transmission Systems	187
8.1.	General Principles of Constructing Quality Detectors	10/
8.2.	Description of Some Methods and Devices for the	100
	Evaluation of Signal Quality	192
8.3.		001
•	Method of Error Detection	201
	1 Webbered 1 December of Come Memor of	
Supplement		209
	Interference	209
C	2. Derivation of a Theorem of Evaluations	217
Supplement	2. Derivation of a Theorem of Evaluations	217
Supplement	3. Modeling of an Error Flow	218
Dapprement	o,	
Supplement	4. Evaluation of the Effectiveness of the Integral	
FF	Method of Registration in Selecting a Step	
	Weight Function	221
	.	

13

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Supplement 5. Determination of the Quality of the Decoding of Group Codes	223
Bibliography	225
Subject Index	233
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10,233 CSO: 1860	

PUBLICATIONS

UDC 621.396.667.83

SCREENING OF MICROWAVE STRUCTURES

Moscow EKRANIROVANIYE SVCH KONSTRUKTSIY [Screening of Microwave Structures] in Russian 1979 signed to press 26 Feb 79 pp 2, 134-135

[Annotation and table of contents from book by Yevgeniy Aleksandrovich Vorob'yev, Sovetskoye radio, 10,000 copies, 135 pages]

[Text] The author examines the problems of electromagnetic compatibility and electric sealing of standard microwave devices. He gives detailed explanations of the method of calculation and practical techniques of designing microwave screens, simple and complex electrically sealed waveguide microwave devices and mirror antennas with a lowered level of internal noise and with a high mutual isolation.

The book is intended for developers, designers, and technologists working in the area of microwave techniques, as well as for students of higher educational institutions.

Tables -- 4, figures -- 51, bibliography -- 46 items.

Contents

		Page
For	reword ·	3
1.	Design Problems of Screening and Electrical Sealing in	
	Standard Microwave Devices	5
	1.1. Outer and Inner Electromagnetic Situation	5
	1.2. Special Characteristics of Ensuring EMS [Electro-	
	magnetic Compatibility] in the Designs of Micro-	
	wave Devices	7
	1.3. Main Design Problems of Ensuring EMS	9
	1.4. Parameters and Characteristics for Quantitative	
	Evaluation of EMS	17
2.	Physical Principles of Screening and Electrical Sealing of	
	Microwave Structures	19
	2.1. Characteristics of the Electromagnetic Field and	
	Peculiarities of the Microwave Range	19

15

	2.2.	Electromagnetic Waves in Isotropic and Homogeneous Media with Losses	23
•	2.3.	Electromagnetic Waves on a Planar Air-Conductor	23
		Interface. Physical Principles of the Operation	
		of Metal Screens	27
	2.4.	Passage of Electromagnetic Waves Through Dielectric	
		Panels. Physical Principles of Operation of Dielec-	
		tric Screens	33
3.	Desig	ning of Screens and Electrically Sealed Casings	38
-	3.1.	Technical Requirements for Electromagnetic	30
		Screens and Electrically Sealed Casings	38
	3.2.	Design Calculations of Homogeneous Screens	40
	3.3.	Design Calculations of Multilayered Screens	54
	3.4.		58
	3.5.		
		the Criteria for the Selection of Materials for	
		Microwave Screens and Electrically Sealed Casings	67
	3.6.	Special Characteristics of the Use of Radio-	
		absorbing Materials, Metal and Dielectric Screens	
		in Microwave Antennas	74
	3.7.		
		Sealed Casings, and Absorbing Materials	85
4.	Desig	n of Electrically Sealed Junctions	89
	4.1.	Selection of the Design Type for Electrically Sealed	
		Waveguide Junctions	89
	4.2.	Technological Design Requirements for Electrically	
		Sealed Waveguide Junctions	95
	4.3.	Electrical Strength of the Designs of Joining	
		Elements of Waveguides	100
	4.4.	Layout of Microwave Circuits of Waveguide	
	, -	Assemblies and Elements	104
	4.5.	Fundamentals of the Theory of Geometrical Layout of	
	4.6.	Complex Waveguide Microwave Circuits	115
	4.0.	Layout of Waveguide Microwave Circuits by the Criterion	
	4.7.	of Electromagnetic Compatibility Control of the Electrical Sealing of Microwave Con-	122
	7./.	nections	100
		100020119	128
Bib	liogra	phy	131
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16

PUBLICATIONS

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SUPERLONG-DISTANCE PROPAGATION OF SHORT RADIO WAVES

Moscow SVERKHDAL'NEYE RASPROSTRANENIYE KOROTKIKH RADIOVOLN [Superlong-Distance Propagation of Short Radio Waves] in Russian 1979 signed to press 26 Mar 79 pp 2, 3-4

[Annotation and table of contents from a book by Aleksandr Viktorovich Gurevich and Yelena Yevgen'yevna Tsedilina, Nauka, 3,650 copies, 248 pages]

[Text] This book is a systematic presentation of the theory of long-distance propagation of short radio waves. Special attention is given to the investigation of global regularities of the propagation of radio waves and development of detailed methods for calculating radio paths. The problems of the capture of radio waves radiated from the earth in an interlayer waveguide channel and exit from the channel with consideration from the effects of inhomogeneities artificially created in the ionosphere when it is perturbed by high-power radio waves are discussed in details.

Tables -- 17, bibliography -- 232 items, figures -- 97.

Contents

Foreword	
Chapter I. Introduction	7
 Around-the-World Signals 	7
Special Characteristics of the Propagation	n of
Radio Waves at Long Distances	15
Chapter II. Spherically Symmetric Ionosphere	20
 Wave Equation in a Spherically Symmetric I 	Conosphere 20
4. Radio Wave Field in An Ionospheric Channel	25
5. Leakage of Radio Waves Through the Barrier	s Between
Channels. Capturing Factor	29
6. Beam Trajectories. Pulse Propagation	31
Chapter III. Horizontally Inhomogeneous Ionospher	re 35
7. Geometrical Optics	35
8. Adiabatic Approximation	30

17

9. Lateral Deviations of Radio Wave Trajectories	47
10. Capture of Radio waves in An Tonospheric Capture (Capture Capture Captu	51
Chapter IV. Regularities of Superlong-Distance Propagation	
s nedda Mayos in the Ionosphere	59
11. Investigation of Global Characteristics of Distant	
Propagation	59
to Alexandra of Padio Wayes	81
13 Calculation of Long-Distance Radio Paths by the	97
Adiabatic Invariant Method	97
	111
Chapter V. Radio Wave Scattering	111
14. Effects of Scattering on the Capture of Radiation	111
i- the Channel	111
15. Effects of Multihop Scattering on the Propagation	124
of Radio Waves in the Channel	
	142
Chapter VI. Nonlinear Phenomena	142
16. Regular Nonlinear Refraction	151
17. Nonlinear Scattering of Radio Waves	
Supplement 1. Distribution of the Radio Wave Field in	
Connected Waveguide Channels	166
Connected waveguide ondinions	
Supplement 2. Analytical Models of Ionospheric Parameters	174
1. Three-Dimensional Model of the Distribution of Electron	
- Colm Londonnere	175
2. Three-Dimensional Model of the Distribution of Effective	
Frequency of Electron Collisions	185
Supplement 3. Wave Theory of the Propagation of Short Radio	
Waves in Horizontally Inhomogeneous Ionosphere.	105
N D Rorisov A. V. Gurevich	195
1 Wave Equation in a Weakly Inhomogeneous Ionosphere	196
o Owesi-Sphorical Approximation	198
3. Interaction of Quasi-Spherical Modes in a Real	100
Tonosphere	199 201
A Adjabatic Modes of Ionospheric Waveguides	201
5. Capture of Radio Waves in a Channel	211
	223
Additions	
	236
Bibliography	
COPYRIGHT: Nauka, Glavnaya redaktsiya fizikomatematicheskoy litera	tury, 197
[139-10233]	
[132-10733]	
10,233	
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18